

<b>Notice of References Cited</b>	Application/Control No. 10/565,532		Applicant(s)/Patent Under Reexamination ARITAKE ET AL.	
	Examiner Vivian Chen		Art Unit 1794	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 15-094585	04-2003	JP	Toyoda et al	
	O	JP 10-151715	06-1998	JP	Oya et al	
	P	JP 15-062933	03-2003	JP	Miyamoto et al	
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

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